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Dimensional Optical Metrology and Inspection for Practical Applications XI

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Contents

v *Conference Committee*

3D AND 4D IMAGING METHODS AND APPLICATIONS I

- 12098 02 **Flexible and accurate phase-to-coordinate calibration method** [12098-2]
- 12098 03 **Absolute three-dimensional shape measurement combining digital image correlation and phase-shifting methods** [12098-3]

3D AND 4D IMAGING METHODS AND APPLICATIONS II

- 12098 04 **High-precision optical coordinate metrology for punching tools by using a digital twin for the measurement strategy (Invited Paper)** [12098-5]
- 12098 05 **Removal of phase artifacts from high-contrast texture for 3D fringe projection system** [12098-7]
- 12098 06 **Data extraction means for advanced optical range metrology** [12098-9]

3D AND 4D IMAGING METHODS AND APPLICATIONS III

- 12098 07 **Real-time 3D video imaging with adaptive phase unwrapping method** [12098-11]

3D AND 4D IMAGING METHODS AND APPLICATIONS IV

- 12098 08 **Design methodology and evaluation of a high performance MWIR interferometer** [12098-29]
- 12098 09 **Optimal window selection for obtaining an extended-depth-of-focus image from white light interference microscopy images** [12098-13]
- 12098 0A **Toward high accuracy measurements in structured light systems** [12098-14]
- 12098 0B **Human-robot interaction booth with shape-from-silhouette-based real-time proximity sensor (Orbbec Best Paper)** [12098-15]
- 12098 0C **Robust counting of engine blades in aircraft engine video endoscopy** [12098-16]

12098 OD **Optimisation of a stereo image analysis by densify the disparity map based on a deep learning stereo matching framework (Orbbec Best Student Paper)** [12098-17]

NEXT-GENERATION SPECTROSCOPIC TECHNOLOGIES AND COMPUTATIONAL IMAGING I

12098 OE **Chemical visualization with optically super-resolved infrared imaging micro-spectroscopy** [12098-19]

12098 OF **A hybrid FTIR/QCL sensing system for gas-phase kinetics using a long-path gas cell (Invited Paper)** [12098-20]

NEXT-GENERATION SPECTROSCOPIC TECHNOLOGIES AND COMPUTATIONAL IMAGING II

12098 OG **Increase of wafer inspection tool throughput with computational imaging** [12098-22]

POSTER SESSION

12098 OH **3D scene description by pretrained features and ICP-based odometry** [12098-25]

12098 OI **Raman spectroscopy and photoluminescence imaging for predictive quality monitoring of CIGS solar cells** [12098-26]

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